

IN THE CLAIMS:

Claims 2 and 3 have been amended herein. All of the pending claims 1 through 3 are presented, pursuant to 37 C.F.R. §§ 1.121(c)(1)(i) and 1.121(c)(3), in clean form below. Please enter these claims as amended. Also attached is a marked-up version of the claims amended herein pursuant to 37 C.F.R. § 1.121(c)(1)(ii).

13/ 1. A testing method for an integrated circuit of an integrated circuit device of a plurality of integrated circuit devices comprising:
storing an enhanced reliability testing flag associated with a unique identification code of each integrated circuit device of the plurality of integrated circuit devices for indicating whether each integrated circuit device requires enhanced reliability testing;
automatically reading the unique identification code of each integrated circuit device of the plurality of integrated circuit devices;
accessing the enhanced reliability testing flag stored for each unique identification code of each integrated circuit device;
sorting the plurality of integrated circuit devices in accordance with whether their enhanced reliability testing flag indicates they are in need of the enhanced reliability testing; and
performing the enhanced reliability testing for the integrated circuit devices requiring the enhanced reliability testing.

CA 21/ 2. (Amended) A reliability testing method for an integrated circuit of an integrated circuit device of a plurality of integrated circuit devices comprising:
storing a reliability testing flag associated with a unique identification code of each integrated circuit device of the plurality of integrated circuit devices for indicating whether each integrated circuit device requires further reliability testing;
automatically reading the unique identification code of each integrated circuit device of the plurality of integrated circuit devices;

accessing the reliability testing flag stored for each unique identification code of each integrated circuit device;
sorting the plurality of integrated circuit devices in accordance with whether their reliability testing flag indicates they are in need of the further reliability testing; and
performing the further reliability testing for the integrated circuit devices requiring the further reliability testing.

3. (Amended) A manufacturing method for an integrated circuit of an integrated circuit device of a plurality of integrated circuit devices comprising:
storing a reliability testing flag associated with a unique identification code of each integrated circuit device of the plurality of integrated circuit devices for indicating whether each integrated circuit device requires further reliability testing;
automatically reading the unique identification code of each integrated circuit device of the plurality of integrated circuit devices;
accessing the reliability testing flag stored for each unique identification code of each integrated circuit device;
sorting the plurality of integrated circuit devices in accordance with whether their reliability testing flag indicates they are in need of the further reliability testing; and
performing the further reliability testing for the integrated circuit devices requiring the further reliability testing.